



Product Change Notification / BLAS-26KOZC951

Date:

17-Apr-2024

Product Category:

Linear Regulators

PCN Type:

Manufacturing Change

Notification Subject:

CCB 6542 Final Notice: Qualification of HANA as an additional assembly site for MCP1793T-3302H/DC, MCP1793T-3302H/DCVAO, MCP1793T-4102H/DC, MCP1793T-4102H/DCVAO, MCP1793T-5002H/DC and MCP1793T-5002H/DCVAO catalog part numbers (CPN) available in 5L SOT-223 package.

Affected CPNs:

[BLAS-26KOZC951_Affected_CPN_04172024.pdf](#)

[BLAS-26KOZC951_Affected_CPN_04172024.csv](#)

Notification Text:

PCN Status:Final Notification

PCN Type:Manufacturing Change

Microchip Parts Affected:Please open one of the files found in the Affected CPNs section.

Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change:Qualification of HANA as an additional assembly site for MCP1793T-3302H/DC, MCP1793T-3302H/DCVAO, MCP1793T-4102H/DC, MCP1793T-4102H/DCVAO, MCP1793T-5002H/DC and MCP1793T-5002H/DCVAO catalog part numbers (CPN) available in 5L SOT-223 package.

Pre and Post Change Summary:

Method to Identify Change:Traceability code

Qualification Report:Please open the attachments included with this PCN labeled as PCN_#_Qual_Report.

Revision History:September 27, 2023: Issued initial notification.

April 17, 2024: Issued final notification. Attached the Qualification Report. Provided estimated first ship date to be on May 15, 2024.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachments:

[PCN_BLAS-26KOZC951 Pre and Post Change_Summary.pdf](#)
[PCN_BLAS-26KOZC951_Qual Report.pdf](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to receive Microchip PCNs via email please register for our PCN email service at our [PCN home page](#) select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the [PCN FAQ](#) section.

If you wish to change your PCN profile, including opt out, please go to the [PCN home page](#) select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

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Affected Catalog Part Numbers (CPN)

MCP1793T-3302H/DC

MCP1793T-3302H/DCVAO

MCP1793T-4102H/DC

MCP1793T-4102H/DCVAO

MCP1793T-5002H/DC

MCP1793T-5002H/DCVAO

CCB 6542

Pre and Post Change Summary

PCN# BLAS-26KOZC951



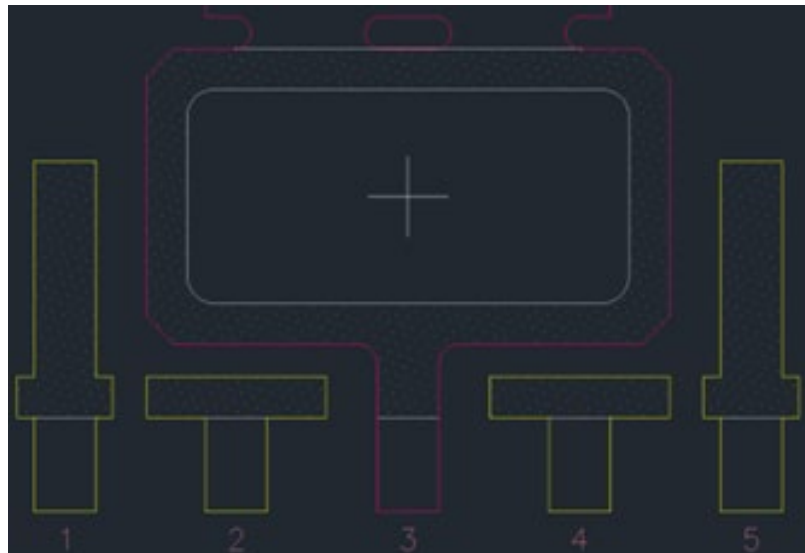
A Leading Provider of Smart, Connected and Secure Embedded Control Solutions



SMART | CONNECTED | SECURE

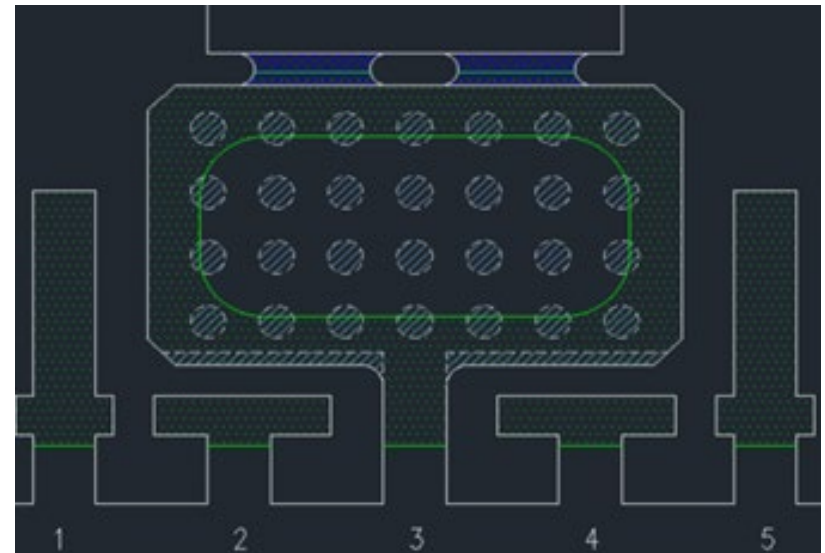
LEAD FRAME COMPARISON

LPI



Note: Not to scale

HANA



Note: Not to scale



QUALIFICATION REPORT SUMMARY
RELIABILITY LABORATORY

PCN #: BLAS-26KOZC951

Date:
April 04, 2024

**Qualification of HANA as an additional assembly site for
MCP1793T-3302H/DC, MCP1793T-3302H/DCVAO,
MCP1793T-4102H/DC, MCP1793T-4102H/DCVAO,
MCP1793T-5002H/DC and MCP1793T-5002H/DCVAO catalog
part numbers (CPN) available in 5L SOT-223 package.**



MICROCHIP

PACKAGE QUALIFICATION REPORT

Purpose	Qualification of HANA as an additional assembly site for MCP1793T-3302H/DC, MCP1793T-3302H/DCVAO, MCP1793T-4102H/DC, MCP1793T-4102H/DCVAO, MCP1793T-5002H/DC and MCP1793T-5002H/DCVAO catalog part numbers (CPN) available in 5L SOT-223 package.
CN	E000196445
QUAL ID	R2301838 Rev. A
MP CODE	VA9B1JN7XVB1
Part No.	MCP1793T-5002H/DCVAO
Bonding No.	BD-001725 Rev. 01
CCB No.	6542
<u>Package</u>	
Type	5L SOT-223
<u>Lead Frame</u>	
Paddle size	152 x 86 mils
Material	C194
Surface	Ring Ag
Process	Etch
Lead Lock	No
Part Number	134761B
Treatment	Rough (BOT)
<u>Material</u>	
Epoxy	84-1LMISR4
Wire	Au wire
Mold Compound	G600
Plating Composition	Matte Sn



MICROCHIP **PACKAGE QUALIFICATION REPORT**

Manufacturing Information

Assembly Lot No.	Wafer Lot No.	Date Code
HANA242900004.000	TC08924167273.800	2342YWB
HANA242900005.000	TC08924167273.800	2342YWD
HANA242900006.000	TC08924167273.800	2342YWQ

Result☒

Pass

☐

Fail

☐

5L SOT-223 assembled by HANA pass reliability test per QCI-39000. This package qualified the Moisture/Reflow Sensitivity Classification Level 1 at 260°C reflow temperature per IPC/JEDEC J-STD-020E standard.

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
<u>Precondition</u> <u>Prior Perform</u> <u>Reliability Tests</u> (At MSL Level 1)	Electrical Test: +25°C, 85°C, 125°C and 150°C System: ETS88	JESD22-A113	693(0)	0/693		Good Devices
	Bake 150°C, 24 hrs. System: CHINEE	JIP/IPC/JEDEC J-STD-020E		693		
	85°C/85%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH			693		
	3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243			693		
	Electrical Test: +25°C, 85°C, 125°C and 150°C System: ETS88		693(0)	0/693	Pass	

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
Temp Cycle	Stress Condition: -55°C to +150°C, 1000 Cycles System: TABAI ESPEC TSA-70H	JESD22-A104		0/231		Parts had been pre-conditioned at 260°C
	Electrical Test: +85°C, 125°C and 150°C System: ETS88		231(0)	0/231	Pass	77 units / lot
	Stress Condition: -55°C to +150°C, 2000 Cycles System: TABAI ESPEC TSA-70H			0/231		
	Electrical Test: +85°C, 125°C and 150°C System: ETS88		231(0)	0/231	Pass	77 units / lot
UNBIASED-HAST	Bond Strength: Wire Pull (>5.00 grams)	JESD22-A118	15(0)	0/15	Pass	
UNBIASED-HAST	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X	JESD22-A118		0/231		Parts had been pre-conditioned at 260°C
	Electrical Test: +25°C System: ETS88		231(0)	0/231	Pass	77 units / lot
HAST	Stress Condition: +130°C/85%RH, 96 hrs. Bias Volt: 35 Volts System: HAST 6000X	JESD22-A110		0/231		Parts had been pre-conditioned at 260°C
	Electrical Test: +25°C, 85°C, 125°C and 150°C System: ETS88		231(0)	0/231	Pass	77 units / lot

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
High Temperature Storage Life	Stress Condition: Bake 175°C, 1000 hrs. System: TPS Bake Oven Electrical Test: +25°C, 85°C, 125°C and 150°C System: ETS88	JESD22- A103	45(0)	0/45 0/45	Pass	45 units
Solderability Temp 215°C	Steam Aging: Temp 93°C, 8Hrs System: SAS-3000 Solder Dipping: Solder Temp.215°C Solder material: SnPb Sn63, Pb37 System: ERSA RA 2200D Visual Inspection: External Visual Inspection	J-STD-002	22(0)	0/22 0/22 0/22	Pass	
Solderability Temp 245°C	Steam Aging: Temp 93°C, 8Hrs System: SAS-3000 Solder Dipping: Solder Temp.245°C Solder material: Pb Free Sn 95.5Ag3.9 Cu0.6 System: ERSA RA 2200D Visual Inspection: External Visual Inspection	J-STD-002	22(0)	0/22 0/22 0/22	Pass	
Physical Dimensions	Physical Dimension, 10 units / 1 lot	JESD22- B100/B108	30(0) Units	0/30	Pass	
Bond Strength Data Assembly	Wire Pull (>5.00 grams) Bond Shear (>9.86 grams)	Mil. Std. 883-2011 CDF-AEC- Q100-001	30(0) Wires 30(0) bonds	0/30 0/30	Pass Pass	